## **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

APPARATUS AND METHOD FOR MANIPULATING SAMPLE TEMPERATURE FOR FOCUSED ION BEAM PROCESSING

Application Number :

Confirmation Number:

First Named Applicant: Chad Rue

Attorney Docket Number: FIS920040175US1

Art Unit: Examiner:

Search string: (6365905 or 20040060904 or 20040112857 or 20040129879 or 20040132287 ).pn

## **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

	init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
ſ		1	6365905	2002-04-02	KOYAMA, ET AL.			

## **US Published Applications**

Note: Applicant is not required to submit a paper copy of cited US Published Applications

ı	init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
Γ		1	20040060904	2004-04-01	HERSCHBEIN, ET AL.			
ŀ		2	20040112857	2004-06-17	HERSCHBEIN,			
l			20040112037	2004-00-17	ET AL.			
Γ		3	20040129879	2004-07-08	FURIKI, ET AL.			
ſ		4	20040132287	2004-07-08	FISCHER, ET			
					AL.			

## **Signature**

Examiner Name	Date